Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/737,281	WEI ET AL.	
Examiner	Art Unit	
Michael D. Pham	2167	

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH I (INCLUDING SEAR		)
	DATE	EXMR
Updated inventor search	11/16/2006	MP
Updated assignee search	11/16/2006	МР
updated east search	11/16/2006	MP
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